Microscopy Autumn School 2023

October 23rd - 27th

Target attendees: PhD students, Postdocs and technicians

Scope: Advanced methods in Microscopy

Aim: Gain knowledge and training on advanced methods in light and electron microscopy

Organizer: Microscopy CORE Lab Venue: MCL – UNS50 FHML/UM

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Monday 23rd	Tuesday 24th	Wednesday 25th	Thursday 26th	Friday 27th
Morning 9-11	Morning 9-11	Morning 9-11	Morning 9-11	Morning 9-11
Introductory Lectures:	Introductory Lectures:	Introductory Lectures:	Introductory Lectures:	Introductory Lectures:
1. "General introduction" Carmen López-Iglesias 2. "Advanced Light Microscopy" Dimitris Kapsokalyvas	"Transmission Electron Microscopy" 1. "Conventional methods" 2. "Cryo-preparation methods" Carmen López-Iglesias	"Scanning Electron Microscopy" 1. "Principle and applications" 2. "Volume & correlative SEM" Kèvin Knoops	"cryo-EM" 1. "Vitrification & Cryo-Electron Tomography" Navya Premaraj 2. "Single Particle Analysis" Ye Gao	"Image processing" Kèvin Knoops Chris Lewis
Afternoon 12-17 Workshops 1, 2, 3, 4	Afternoon 12-17 Workshops 1, 2, 3, 4	Afternoon 12-17 Workshops 1, 2, 3, 4	Afternoon 12-17 Workshops 1, 2, 3, 4	Afternoon 12-16 Workshop 5

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Workshop number	Title/Instruments and workflows	Teachers and Tutors
Workshop 1	Light Microscopy : Confocal STED superresolution, Two-Photon, Spinning disk	Helma Kuijpers Anne Gemmink Gert Schaart
Workshop 2	TEM : Conventional, Cryo-methods (HPF, freeze/substitution, cryo/sectioning), RT-TEM RT-Tomography, immunolabeling	Willine van de Wetering Elly van Donselaar Carmen López-Iglesias
Workshop 3	SEM : Conventional SEM (+EDX), High Resolution-SEM, FIB-SEM, Slice and view	Hans Duimel Kèvin Knoops
Workshop 4	Cryo-EM : Vitrification, Cryo-SEM, FIB-SEM (cryo-lamella), cryo-TEM for single particle and cryo-electron tomography	Chris Lewis Navya Premaraj Sneha Hakke
Workshop 5	Image processing Image properties, manipulation, quantification & visualization. Microscopy data quality control	Chris Lewis Kèvin Knoops